## Notice of References Cited Application/Control No. 10/531,329 Applicant(s)/Patent Under Reexamination HIRANUMA ET AL. Examiner Diem Tran Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,287,698	02-1994	Shinzawa et al.	60/286
*	В	US-5,319,930	06-1994	Shinzawa et al.	60/286
*	С	US-6,655,133	12-2003	Mikami et al.	60/296
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р				·	
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	R					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	

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